

10/580768
1AP2UR330PC770 25 MAY 2006

SHIGA7.051APC

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Takeshita et al.
Appl. No. : U.S. National Phase of
PCT/JP2004/017405
Filed : Herewith
For : POSITIVE RESIST
COMPOSITION AND METHOD
FOR FORMING RESIST
PATTERN
Examiner : Unassigned
Group Art Unit : Unknown

CERTIFICATE OF MAILING

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

May 25, 2006

(Date)

Neil S. Bartfeld, Ph.D., Reg. No. 39,901

PRELIMINARY AMENDMENT

Mail Stop PCT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Prior to examination of the above-referenced application, please enter the following amendments:

Amendments to the Specification begin on page 2 of this paper.

Remarks begin on page 3 of this paper.